

<b>Notice of References Cited</b>	Application/Control No. 10/670,354	Applicant(s)/Patent Under Reexamination NIWA, TAKEO	
	Examiner Stephen J Stein	Art Unit 1775	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,357,526	11-1982	Yamamoto et al.	219/544
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 61251580 A	11-1986	Japan		C04B 35/58
	O	JP 07010665 A	01-1995	Japan	KAWADA et al.	C04B 41/89
	P	JP 08227933 A	09-1996	Japan	KAWADA et al.	H01L 21/68
	Q	JP 411317441 A	11-1999	Japan	WATANABE et al.	H01L 21/68
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.